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# **Instrumentation and methodology of Scanning Photoemission Microscopy, analyzers and multichannel detection**

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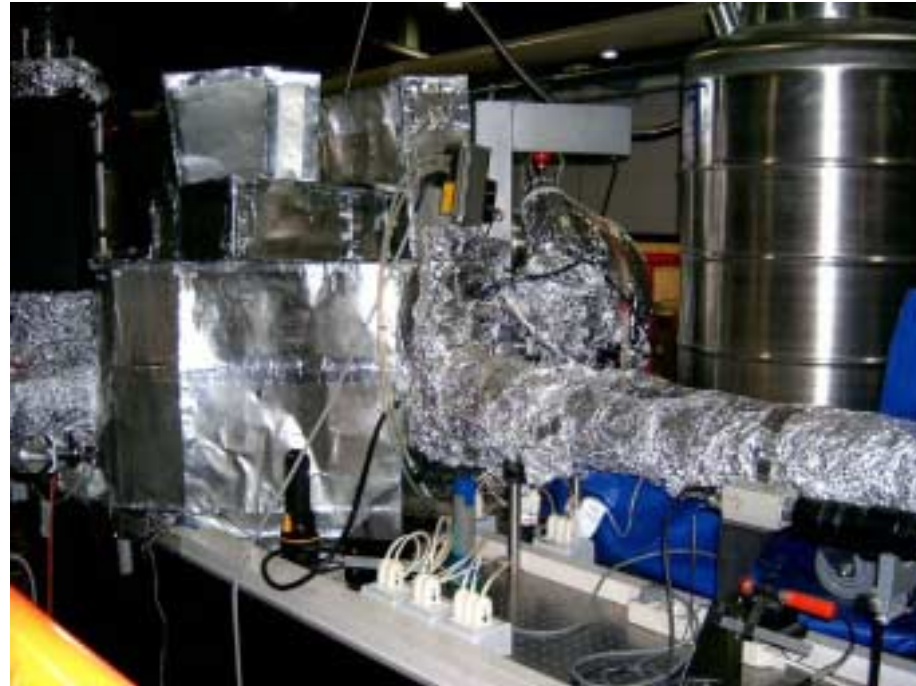
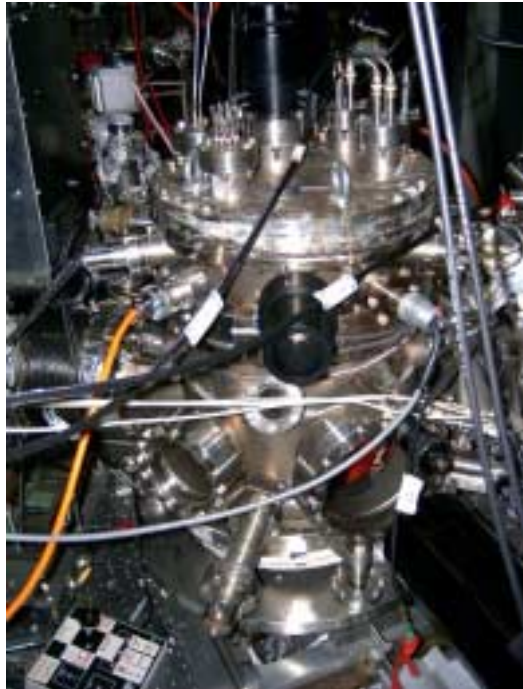
**Outline:**  
**ingredients of a Scanning Photoemission Microscope  
(SPEM) based on Zone Plates**

- Vacuum chambers
- Sample and optics manipulators
- Sample holders
- Electron analyzers
- Electron detectors

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## Vacuum chambers

- No standard geometry
- Dimensions depends mainly from the size of the manipulators
- Large flanges for the manipulators (>CF200)
- Geometry limits the possibility of in-situ experiments



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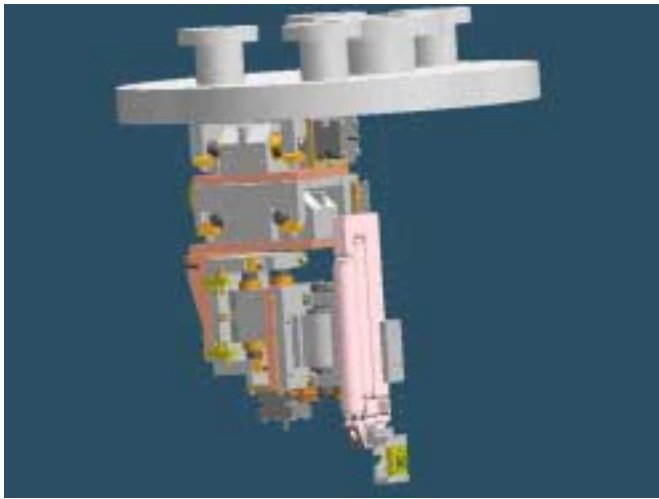
# Manipulators

## Sample

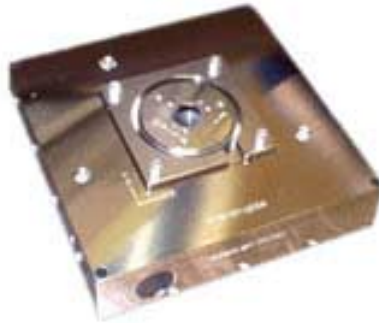
- Large scanning range ( $>1\text{mm}$ ) with large steps ( $1\text{-}100\ \mu\text{m}$ )
- Small scanning range ( $<3\text{mm}$ ) with small steps ( $10\text{-}50\ \text{nm}$ )
- The most common choice is to use two kind of motors: stepper (for large scans) and piezo (for small scans)
- Compact design to improve the stability

## Optics (ZP+OSA)

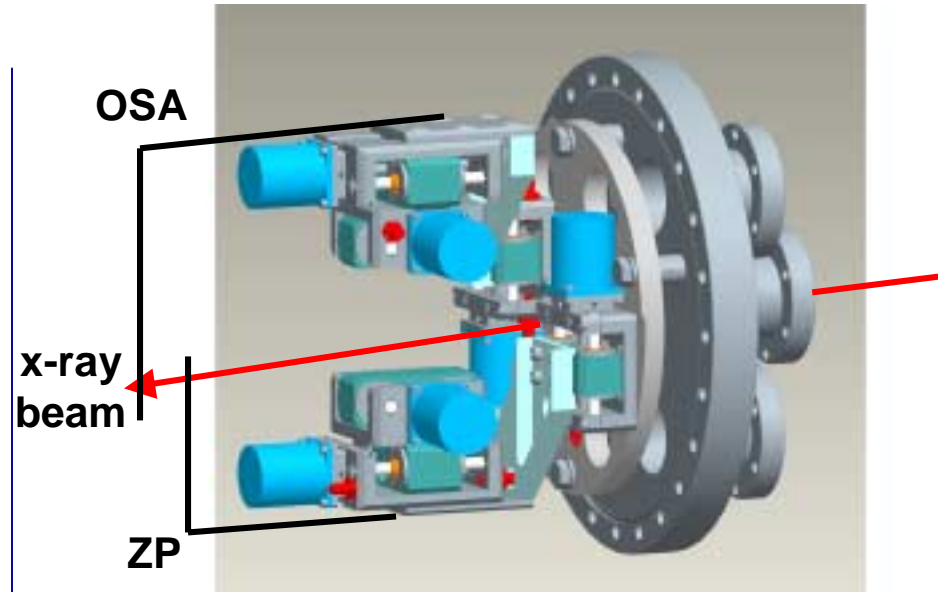
- 6-axis needed: 3 for the ZP and 3 for the OSA
- Typical range:  $10\text{ - }15\ \text{mm}$
- Movement resolution of  $1\text{-}3\ \mu\text{m}$
- Only one type of motors needed (stepper or inchworm)
- Compact design to improve the stability



**x-y piezo stages**



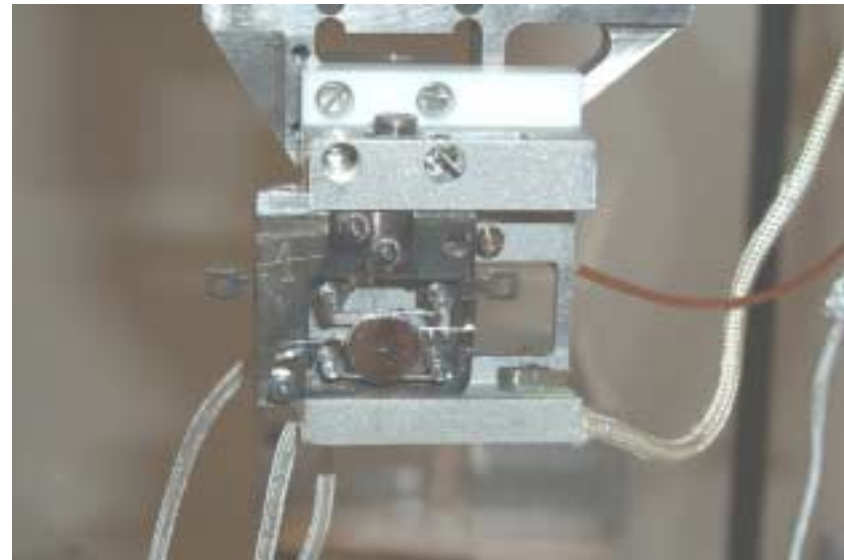
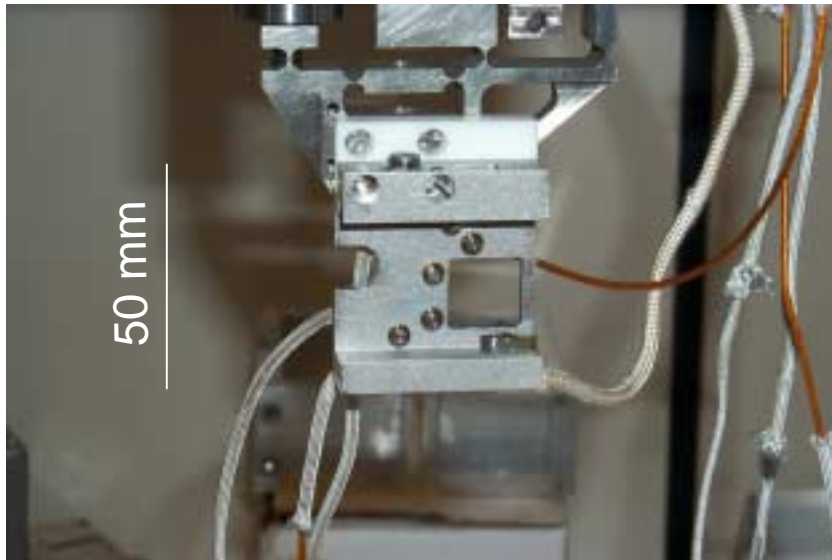
**1 axis coarse translation stage**



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## Sample holders

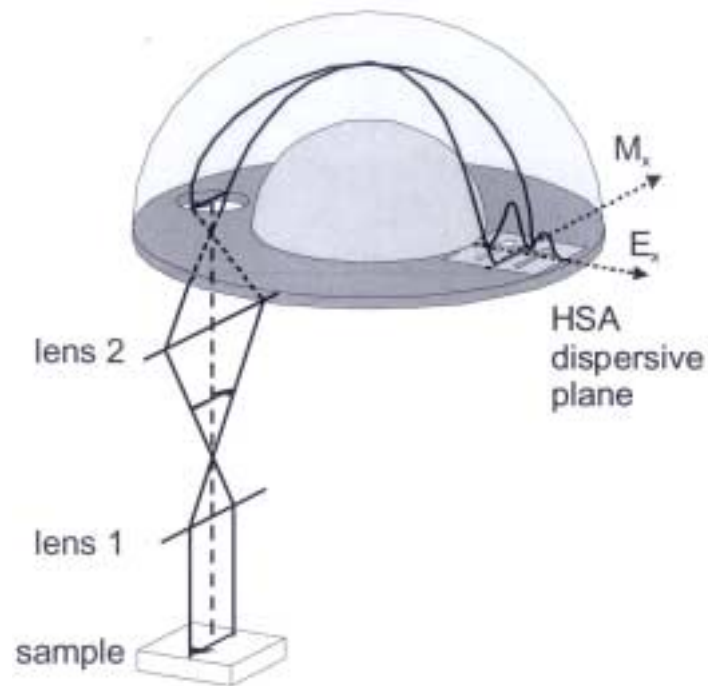
- Cabling used for the contacts (heating, grounding, potentials, etc.) must not interfere with the scanning motion.
- Cooling needs special design
- In most of the cases sample holders are home designed (or modified from standard designs)



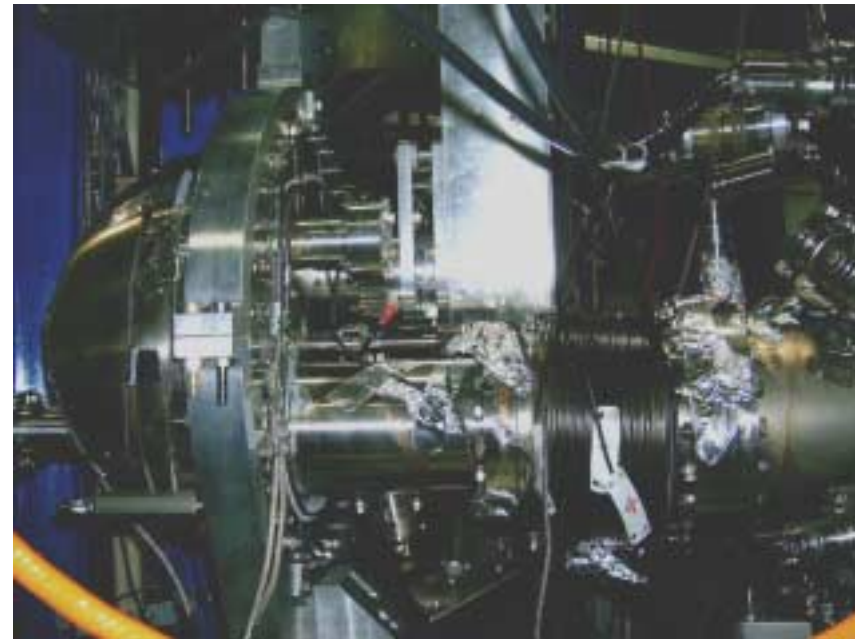
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## Electron analyzers

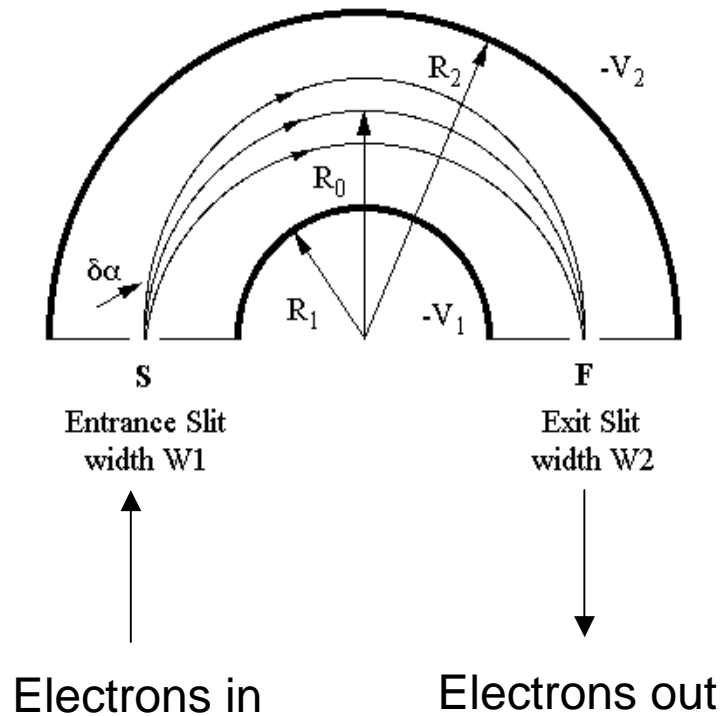
- The most used type of electron analyzer is the Hemispherical Electron Analyzer (HEA)
- Due to geometrical constraints the detection is mainly grazing



Electron analyzer of the SPEM



Potential along the median surface: 
$$V_0 = \frac{V_1 R_1 + V_2 R_2}{2R_0}$$



Tangential injection

$$V_1 = V_0 \frac{R_2}{R_1} \quad V_2 = V_0 \frac{R_1}{R_2}$$

$$E_0 = eV_0$$

Angled injection

$$\Delta R = 2 R_0 \left[ \frac{\Delta E}{E} - (\delta\alpha)^2 \right]$$



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## Electron detectors

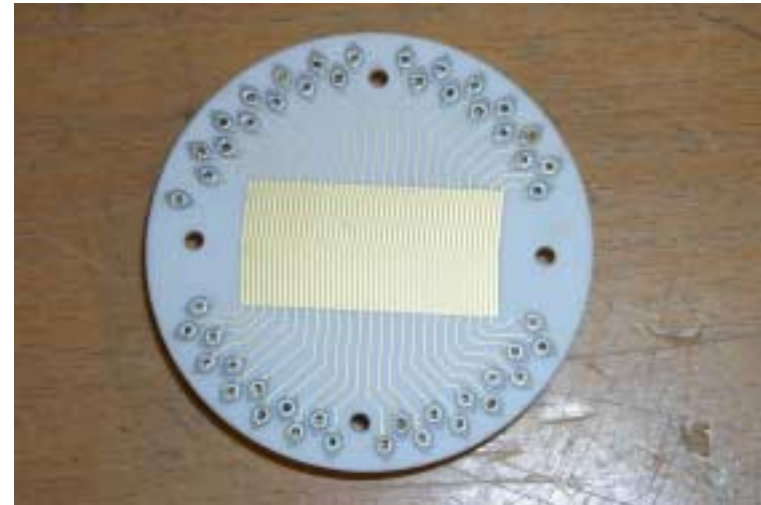
### Single channel

- Single channeltron
- Single Au plated anode
- Not very diffused



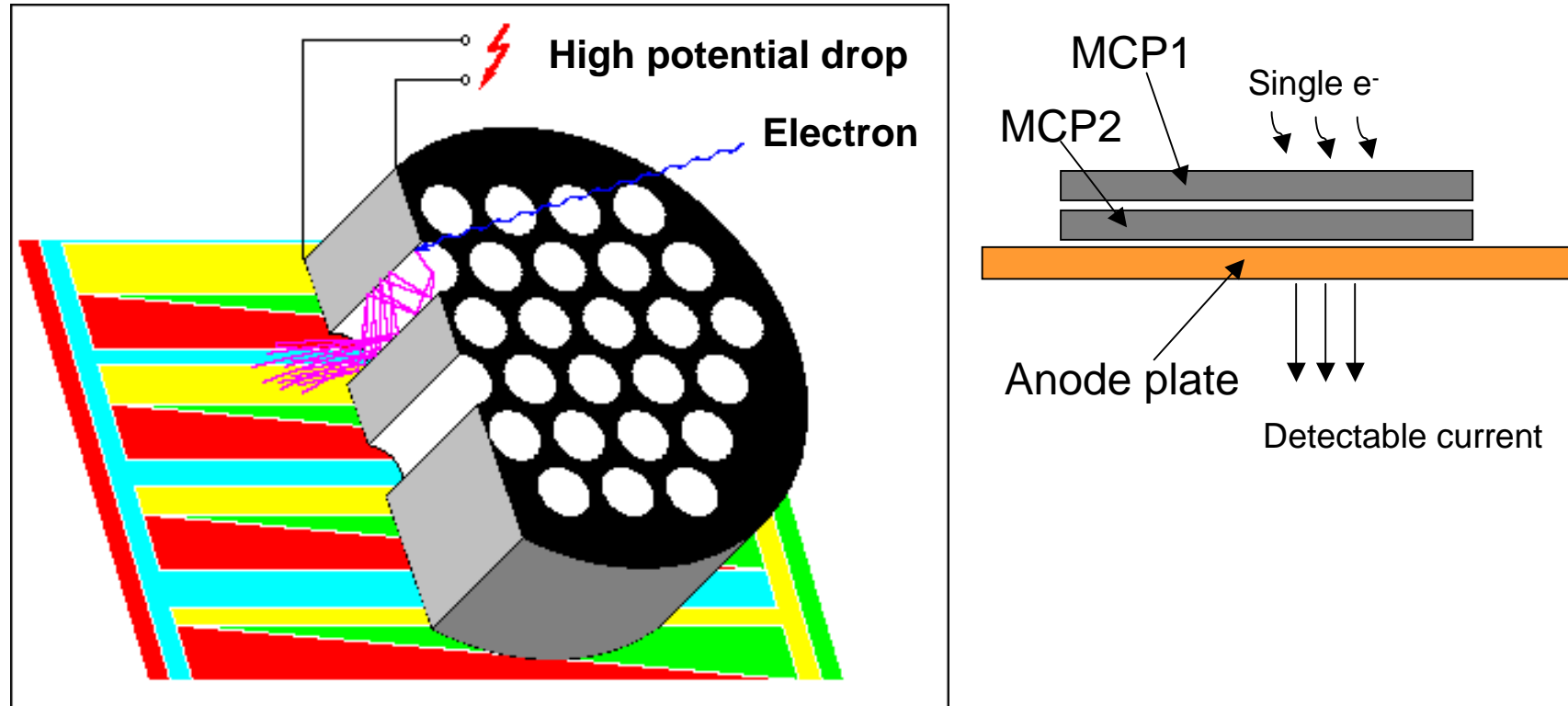
### Multi channel

- Array of channeltron (low number of channels)
- Multi Au plated anodes (100 channels)
- 2D-CCD detectors



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## Electron detectors based on micro channel plates



The Microchannel Plate (MCP) consists of millions of very-thin, conductive glass capillaries (4 to 25 micro meters in diameter) fused together and sliced into a thin plate. Each capillary or channel works as an independent secondary-electron multiplier to form a two-dimensional secondary-electron multiplier.



Vacuum compatible condenser

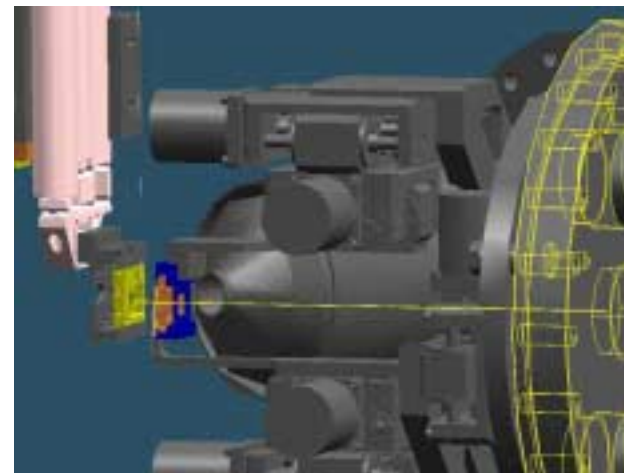
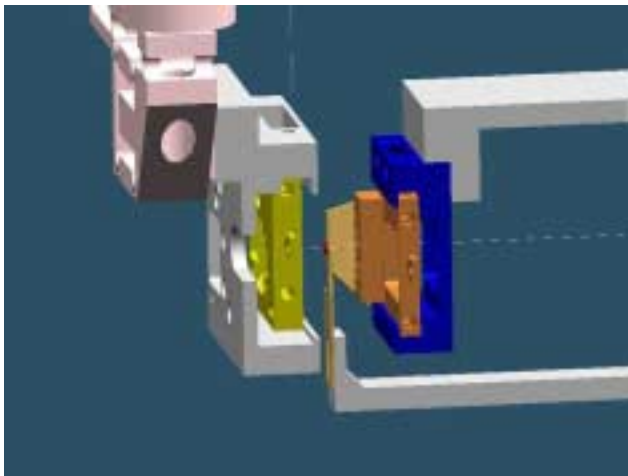
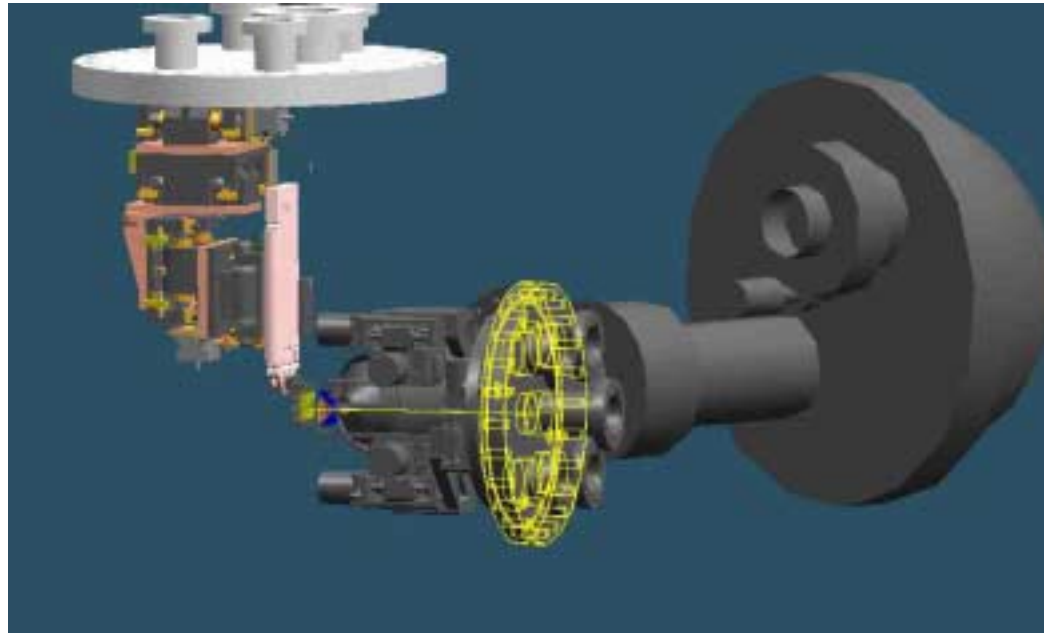


## Electron Detector Electronics

- Discriminators
- Preamplifiers
- Counters

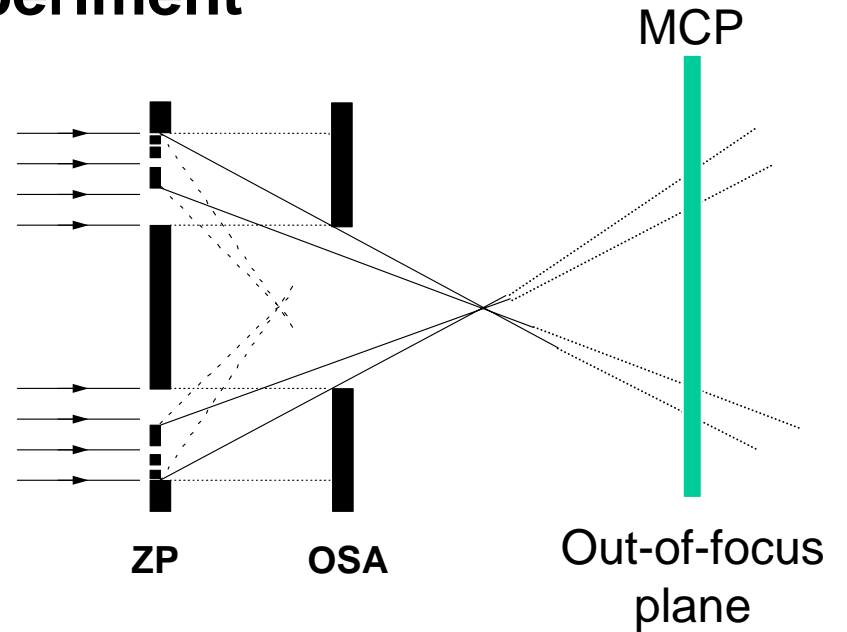
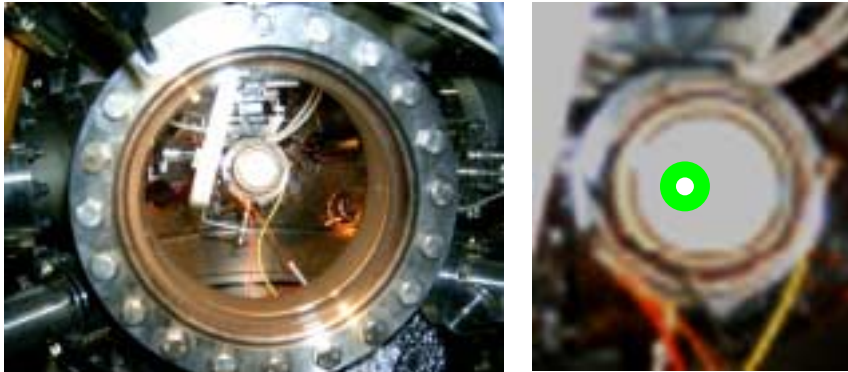
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## Final layout of the experimental chamber



# Start-up of an experiment

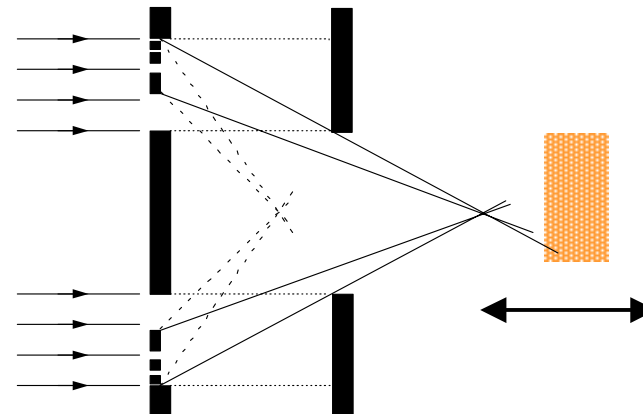
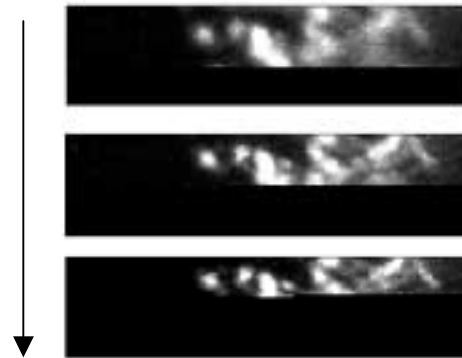
## 1. Optics alignment



## 2. Sample on the x-ray focus

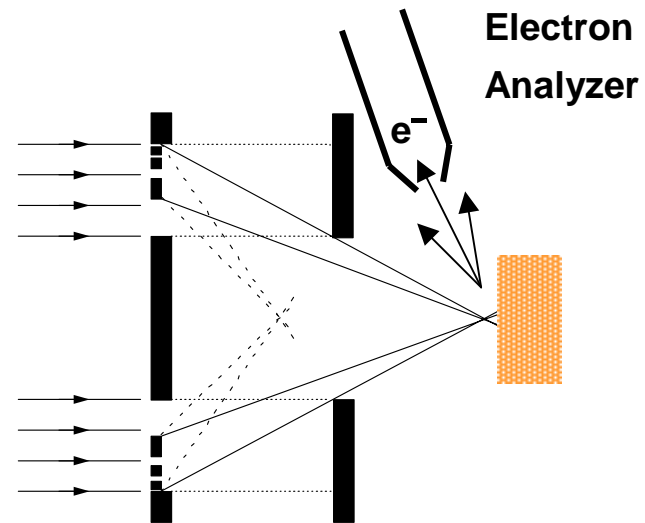
$$DOF = \frac{\delta r}{D} f_m$$

Typical: 5-15 $\mu\text{m}$



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### 3. Analyzer adjustment



### 4. Data acquisition

- Images: electron analyzer set to a fixed energy and sample rastered
- Photoemission Spectra: sample fixed and energies scanned

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## References

S. Guenther, B. Kaulich, L. Gregoratti, M. Kiskinova, "Photoelectron Microscopy and Applications in Surface and Material Science", PROG SURF SCI, 70-, pp. 187-74 (2002).

A.W. Potts, G.R. Morrison, L. Gregoratti, A. Barinov, B. Kaulich, M. Kiskinova, "The exploitation of multichannel detection in scanning photoemission microscopy", SURF REV LETT, 9-2, pp. 705-8 (2002).

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